



MiTAC Digital Technology Corporation

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Date: Feb.12, 2026

FCC Laboratory
7435 Oakland Mills Rd
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SUBJECT: Class II Permissive Change for FCC ID: P4Q-N702, Model: N702

To Whom It May Concern,

We, **MiTAC Digital Technology Corporation**, hereby declare that we are applying for a **Class II Permissive Change** for the above-referenced FCC ID. The subsequently certificate was issued on August 26, 2024.

The purpose of this application is to document the substitution of the NFC RF chip component within the transmitter circuitry and the addition of a brand name. The changes are detailed as follows:

Product Changes

- **Original NFC Chip IC:** NXP NQ310
- **New NFC Chip IC:** NXP NQ410
- The NFC chip IC is replaced with a component of the same brand, model series, and equivalent specifications as the original.
- **Added Brand Name:** Surecam

1. Justification for Class II Permissive Change In accordance with KDB 178919 D01 Permissive Change Policy v06, Section III(D) regarding "Part Substitution", we confirm that this substitution meets the conditions for a Class II Permissive Change:

1. Pin-for-Pin Compatibility: The new chip is pin-for-pin compatible with the original chip.
2. Electrically Identical Function: The new chip serves the same basic function and is electrically identical from an external perspective.
3. Equivalent PCB Area: The replacement involves an equivalent chip occupying the same area on the PCB.
4. Verification of Compliance (FCC Part 15.225) To demonstrate that no change in radio parameters has occurred (Condition 3 of the cited KDB), we have performed a comprehensive re-verification of all applicable FCC Part 15.225 test items, including:
 - Fundamental Field Strength
 - Spurious Emissions
 - Frequency Stability

Conclusion of Test Results: The evaluation confirms that the RF characteristics remain consistent with the original filing. All measured levels are within the limits of the original grant and do not exceed the originally authorized parameters. No degradation in performance was observed.

Please refer to the enclosed Test Report for detailed measurement data.

Sincerely,

Shin Hui Chou

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